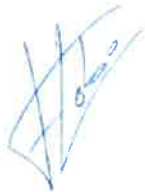

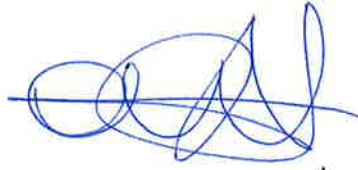


Test Report Summary

No E-17-I-022-FL

PRIME Certification Tests Cases for Service Nodes

EQUIPMENT UNDER TEST	Single-phase service node (PRIME chipset)
MODEL/FW VERSION	SAM4CP16B-EK / v01.04.02.01
CERTIFICATION SCOPE¹	PHY, MAC and Convergence layers. Backwards Compatibility and Security procedures are out of the scope of this certification.
MANUFACTURER	Microchip
APPLICANT	Alfredo Sanz
DATE OF RECEPTION	Torre C2 Polígono Puerta Norte A-23, 50280 Zaragoza, Spain 31 st January, 2017
PRIME SPECIFICATION VERSION/TEST CASE VERSION	PRIME-Specification v1.4 Rev.1 / PRIME Certification SN Tests Cases v2.2
DATE OF EXECUTION	From February 8 th till 23 rd , 2017
DATE OF ISSUE OF REPORT	Brussels, February 27 th , 2017

Responsible for tests	Head of Laboratory	PRIME Alliance Vice President
		
Fernando Lobo	Juan Ignacio Sánchez	Oscar Márquez

- * This test report summary is granted on account of tests made at location of DNVGL Services Spain SL in Madrid, Spain.
- * The results of the present report apply only to the samples tested and the moment and conditions under which the measurements were performed.
- * The complete results, including remarks and limitations, are laid down in our complete test report no. E-17-I-021-FL which can be obtained at DNVGL Services Spain SL. The certificate and the test report are indivisible.
- * The test report summary is issued by PRIME Alliance. It shall not be reproduced, in total or in part and in whatever way, without written permission of DNVGL Services Spain SL.

¹ IMPORTANT: Remarks apply to the implementation of this function. See complete test report no. E-17-I-021-FL (ANNEX I) for full details.